

Docket No.: J&R-0694

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By: 

Date: March 1, 2006

 IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applic. No. : 09/922,479 Confirmation No.: 7212
Applicant : Thomas Zettler
Filed : August 3, 2001
Title : Method and Device for Testing an Integrated Circuit, Integrated Circuit to be Tested, and Wafer with a Large Number of Integrated Circuits to be Tested
Art Unit : 2138
Examiner : Phung M. Chung
Docket No. : J&R-0694
Customer No. : 24131

INFORMATION DISCLOSURE STATEMENT

Hon. Commissioner for Patents
Alexandria, VA 22313-1450

Sir:

In accordance with 37 C.F.R. 1.98 copies of the following patents and/or publications are cited herewith:

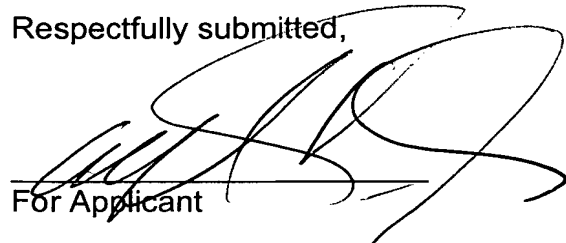
European Patent Application EP 0 803 902 A2 (Terauchi), dated October 29, 1997;

European Examination Report dated February 13, 2006.

In accordance with 37 C.F.R. 1.97(e) the undersigned herewith states that each item of information contained in the information disclosure statement was first cited in a

In accordance with 37 C.F.R. 1.97(e) the undersigned herewith states that each item of information contained in the information disclosure statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the information disclosure statement.

Respectfully submitted,


For Applicant

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Date: March 1, 2006

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FORM PTO-1449 (SUBSTITUTE)

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEINFORMATION DISCLOSURE
STATEMENT BY APPLICANT
(37 CFR 1.98(b))Attorney Docket No.:
J&R-0694Applic. No.
09/922,479

Applicant

Thomas Zettler

Filing Date
August 3, 2001Group Art Unit
2138

U.S. PATENT DOCUMENTS

EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
	A						
	B						
	C						
	D						
	E						
	F						
	G						
	H						
	I						

FOREIGN PATENT DOCUMENT

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES NO
	J	0 803 902 A2	10/1997	Europe			
	K						
	L						
	M						
	N						

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

	O	
	P	

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.